IN THE UNITED STATES PATENT AND TRADEMARK OFFICE 3/13/02 3/15/02

In re amendment to CRAIG PRATER patent application

Serial No. 08/871,029 Examiner: Daniel Larkin

Filed:

June 9, 1997

Art Unit: 2856

For:

SCANNING STYLUS ATOMIC FORCE MICROSCOPE

WITH CANTILEVER TRACKING AND OPTICAL

ACCESS

Assistant Commissioner of Patents Washington, D.C. 20231

SUPPLEMENTAL AMENDMENT

Sir:

Supplementing the Amendment sent on November 13, 2001, and at the request of Examiner Larkin, here are clean copies of claims 71 and 72 as follows:

(amended) The microscope of claim 66, wherein said 71. detection device generates a signal which is processed to create a control signal to servo said motion control device, wherein said control signal is further used in conjunction with applied position signals to create a three dimensional map of the sample surface.

Amendment to D9310A 122101, WPD Friday, December 21, 2001

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